

ABSTRACT

The connection assembly includes an intermediate connection member and a connection substrate stacked on the intermediate connection member. The intermediate connection member includes a plurality of connection pins electrically connecting a plurality of tester-side terminals and a plurality of probe card-side terminals, respectively, a first frame portion holding one end of each of the plurality of connection pins, a second frame portion holding the other end of each of the plurality of connection pins, and a housing space provided in either or both of the first frame portion and the second frame portion. The connection substrate is stacked on either or both of the first frame portion and the second frame portion having the housing space, and includes a conductive part electrically connected to the plurality of connection pins, and an electronic component electrically connected to the conductive part and disposed in the housing space.

FIG. 3